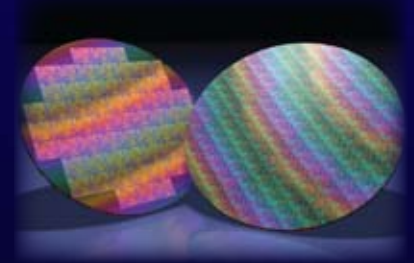
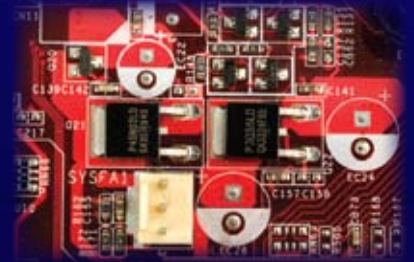


XRF 2000-R



Elemental Analyzer and Coating Thickness X-Ray

- High Resolution, Solid State Detector
- RoHS/WEEE Compliance Testing
- Trace Element Analysis 0.1 – 100%
- Multi-layer Platings Measurement
- Plating Bath Analysis
- Hazardous Materials Detection
- Measures liquids, solids, powders, films and irregular shapes
- Precious metals analysis (gold, silver, platinum, and jewelry)



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X-Ray System Capabilities

- Precious metal alloy assay and element identification
- Trace analysis of hazardous materials
- Coating thickness measurement for multiple layers, or Sn-Pb composition
- RoHS, WEEE and ELV optimized applications
- Qualitative analysis for up to 30 elements
- Large chambers with automatic filters, multiple collimators and XYZ stages

X-Ray System Specifications

Chambers: Multiple models

X-Ray Tube: Micro-Focus 50Kv @ 1.0 mA with W, Ag, Mo or Rh targets

Detector: Silicon, Pin Diode, Peltier cooled

Filters: Up to 6 motorized, primary X-Ray filters

Collimators: Up to 5, from 4.0 mils - 125 mils

Sample Stage: Programmable X-Y-Z with automatic focus, Point & Measure and EZ parts loading features

Data: 5 custom report formats or direct to Excel

Video: Color, Hi-resolution, 20X magnification

Electrical: 110/220V AC 50/60 Hz

Typical Analysis Results

Jewelry Standards

Element	Actual	Measured
Pt	100%	99.99%
Pt	97.0%	97.02%
Au	100%	99.99%
Au	76.3%	76.18%
Au	51.8%	51.67%

PVC Standards

Pb	400 ppm	406 ppm
Cd	100 ppm	102 ppm
Hg	200 ppm	191 ppm
Cd	400 ppm	415 ppm
Br	500 ppm	520 ppm



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